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| Notice of References Cited | Application/Control No. 10/084,019 | Applicant(s)/Patent Under Reexamination TIEDEMANN ET AL. | |
| | Examiner Venkatesh Haliyur | Art Unit 2664 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-2002/0150065 | 10-2002 | Ponnekanti, Sessaiah | 370/334 |
| * | B | US-2004/0013103 | 01-2004 | Zhang et al. | 370/345 |
| * | C | US-6,947,475 | 09-2005 | Sendonaris et al. | 375/148 |
| * | D | US-2003/0171118 | 09-2003 | Miya, Kazuyuki | 455/442 |
| * | E | US-6,208,632 | 03-2001 | Kowalski et al. | 370/335 |
| * | F | US-2002/0101839 | 08-2002 | Farley et al. | 370/329 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
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